

| | | | |
|-----------------------------------|---------------------------------------|---|-------------|
| Notice of References Cited | Application/Control No. 10/774,588 | Applicant(s)/Patent Under Reexamination TANABE ET AL. | |
| | Examiner Victor V. Yevsikov | Art Unit 2891 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|-----------------|----------------|
| | A | US-4,579,723 | 04-1986 | Weltmer et al. | 423/219 |
| | B | US-4,836,929 | 06-1989 | Baumann et al. | 210/638 |
| | C | US-4,668,260 | 05-1987 | Yoshino, Akira | 62/656 |
| | D | US-5,686,345 | 11-1997 | Harmon et al. | 438/702 |
| | E | US-5,716,871 | 02-1998 | Yamazaki et al. | 438/635 |
| | F | US-5,861,347 | 01-1999 | Maiti et al. | 438/787 |
| | G | US-5,777,300 | 07-1998 | Homma et al. | 219/679 |
| | H | US-5,244,843 | 09-1993 | Chau et al. | 438/452 |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.